



STGW12NB60H

N-CHANNEL 12A - 600V TO-247
PowerMESH™ IGBT

PRELIMINARY DATA

TYPE	V _{CES}	V _{CE(sat)}	I _C
STGW12NB60H	600 V	< 2.8 V	12 A

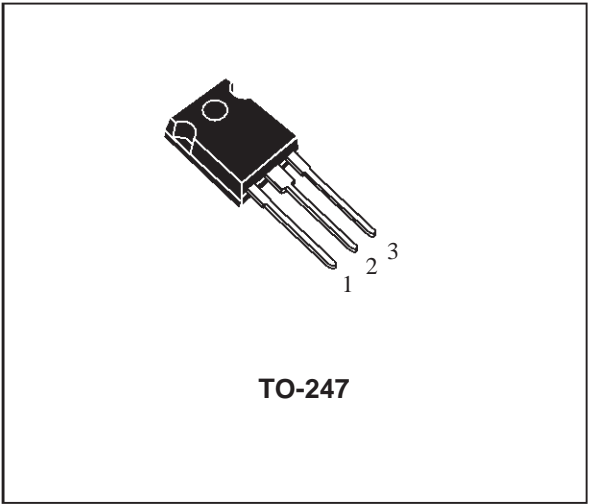
- HIGH INPUT IMPEDANCE (VOLTAGE DRIVEN)
- LOW ON-VOLTAGE DROP (V_{CESAT})
- LOW GATE CHARGE
- HIGH CURRENT CAPABILITY
- VERY HIGH FREQUENCY OPERATION
- OFF LOSSES INCLUDE TAIL CURRENT

DESCRIPTION

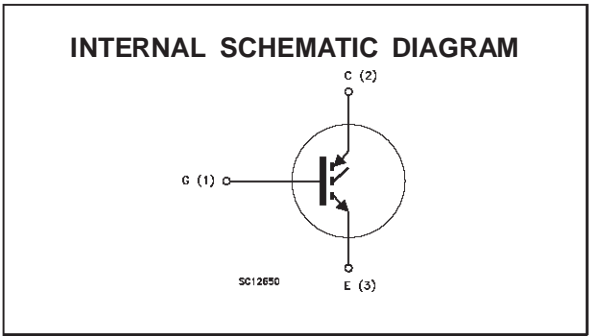
Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the PowerMESH™ IGBTs, with outstanding performances. The suffix "H" identifies a family optimized to achieve very low switching times for high frequency applications (<120kHz).

APPLICATIONS

- HIGH FREQUENCY MOTOR CONTROLS
- SMPS AND PFC IN BOTH HARD SWITCH AND RESONANT TOPOLOGIES



TO-247



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{CES}	Collector-Emitter Voltage (V _{GS} = 0)	600	V
V _{ECR}	Emitter-Collector Voltage	20	V
V _{GE}	Gate-Emitter Voltage	± 20	V
I _C	Collector Current (continuous) at T _c = 25 °C	24	A
I _C	Collector Current (continuous) at T _c = 100 °C	12	A
I _{CM} (•)	Collector Current (pulsed)	96	A
P _{tot}	Total Dissipation at T _c = 25 °C	120	W
	Derating Factor	0.96	W/°C
T _{stg}	Storage Temperature	-65 to 150	°C
T _j	Max. Operating Junction Temperature	150	°C

(•) Pulse width limited by safe operating area

STGW12NB60H

THERMAL DATA

R _{thj-case}	Thermal Resistance Junction-case	Max	1.04	°C/W
R _{thj-amb}	Thermal Resistance Junction-ambient	Max	30	°C/W
R _{thc-h}	Thermal Resistance Case-heatsink	Typ	0.1	°C/W

ELECTRICAL CHARACTERISTICS (T_j = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{BR(CES)}	Collector-Emitter Breakdown Voltage	I _C = 250 μA V _{GE} = 0	600			V
I _{CES}	Collector cut-off (V _{GE} = 0)	V _{CE} = Max Rating T _j = 25 °C V _{CE} = Max Rating T _j = 125 °C			10 100	μA μA
I _{GES}	Gate-Emitter Leakage Current (V _{CE} = 0)	V _{GE} = ± 20 V V _{CE} = 0			± 100	nA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{GE(th)}	Gate Threshold Voltage	V _{CE} = V _{GE} I _C = 250 μA	3		5	V
V _{CE(SAT)}	Collector-Emitter Saturation Voltage	V _{GE} = 15 V I _C = 12 A V _{GE} = 15 V I _C = 12 A T _j = 125 °C		2.0 1.7	2.8	V V

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g _{fs}	Forward Transconductance	V _{CE} = 25 V I _C = 12 A		9.5		S
C _{ies} C _{oes} C _{res}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{CE} = 25 V f = 1 MHz V _{GE} = 0		950 120 27		pF pF pF
Q _G Q _{GE} Q _{GC}	Total Gate Charge Gate-Emitter Charge Gate-Collector Charge	V _{CE} = 480 V I _C = 12 A V _{GE} = 15 V		68 10 30		nC nC nC
I _{CL}	Latching Current	V _{clamp} = 480 T _j = 150 °C R _G = 10 Ω	48			A

SWITCHING ON

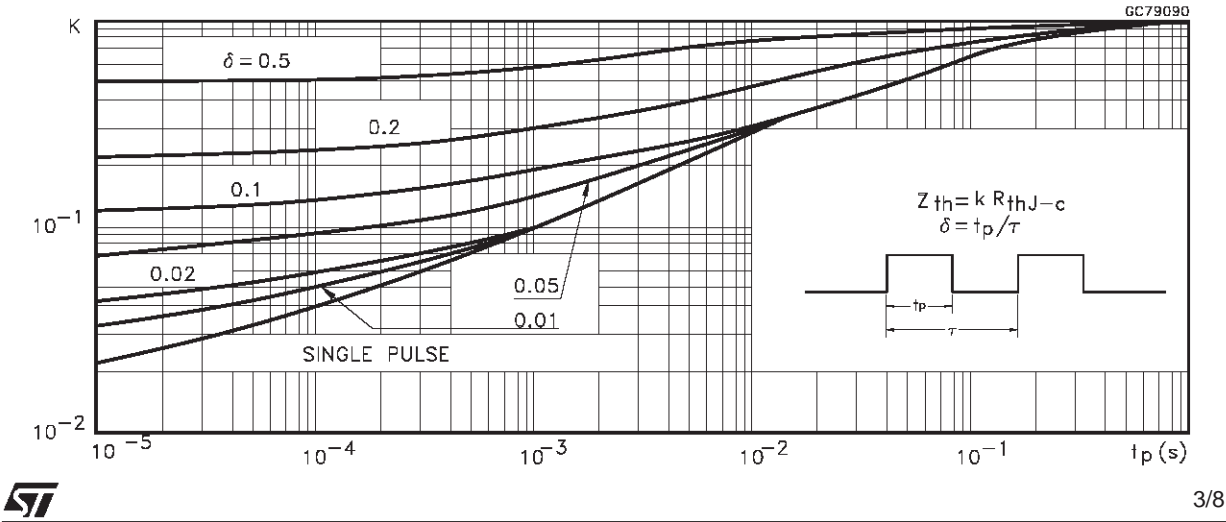
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
t _{d(on)} t _r	Delay Time Rise Time	V _{CC} = 480 V I _C = 12 A V _{GE} = 15 V R _G = 10 Ω		5 46		ns ns
(di/dt) _{on}	Turn-on Current Slope	V _{CC} = 480 V I _C = 12 A R _G = 10 Ω V _{GE} = 15 V		1000		A/μs
E _{on}	Turn-on Switching Losses	T _j = 125 °C		290		μJ

ELECTRICAL CHARACTERISTICS (continued)
SWITCHING OFF

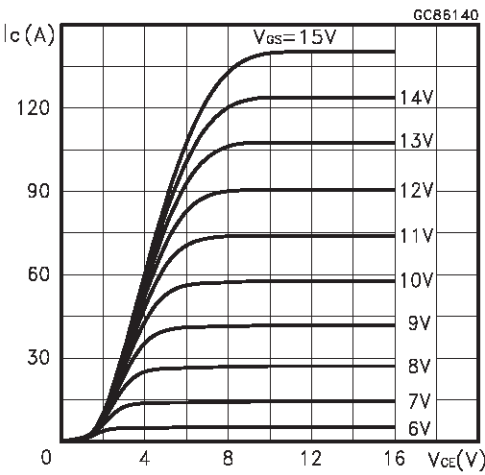
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
t_c	Cross-Over Time	$V_{CC} = 480\text{ V}$ $R_{GE} = 10\ \Omega$ $I_C = 12\text{ A}$ $V_{GE} = 15\text{ V}$		150		ns
$t_r(v_{off})$	Off Voltage Rise Time			27		ns
$t_d(off)$	Delay Time			76		ns
t_f	Fall Time			92		ns
$E_{off(**)}$	Turn-off Switching Loss			0.21		mJ
E_{ts}	Total Switching Loss			0.49		mJ
t_c	Cross-Over Time	$V_{CC} = 480\text{ V}$ $R_{GE} = 10\ \Omega$ $T_j = 125\text{ }^\circ\text{C}$ $I_C = 12\text{ A}$ $V_{GE} = 15\text{ V}$		230		ns
$t_r(v_{off})$	Off Voltage Rise Time			76		ns
$t_d(off)$	Delay Time			95		ns
t_f	Fall Time			200		ns
$E_{off(**)}$	Turn-off Switching Loss			0.45		mJ
E_{ts}	Total Switching Loss			0.74		mJ

(●) Pulse width limited by max. junction temperature
(*) Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %
(**) Losses Include Also The Tail (Jedec Standardization)

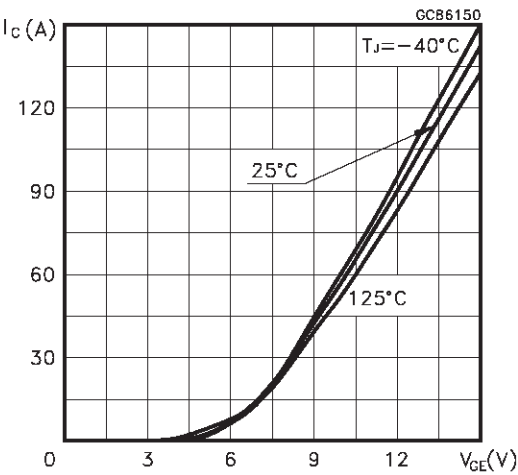
Thermal Impedance



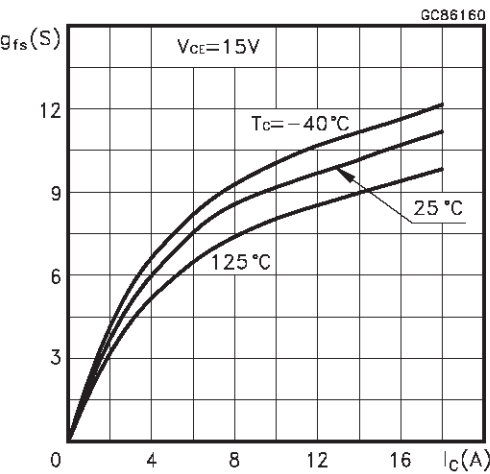
Output Characteristics



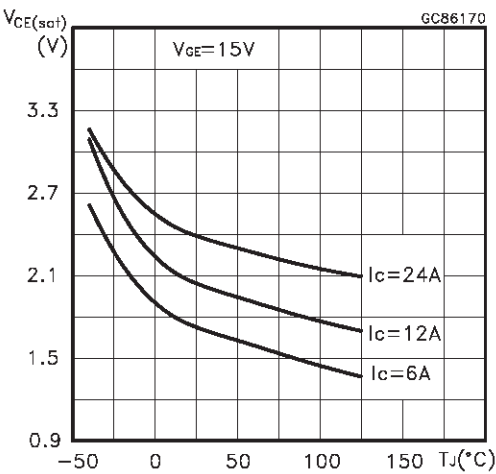
Transfer Characteristics



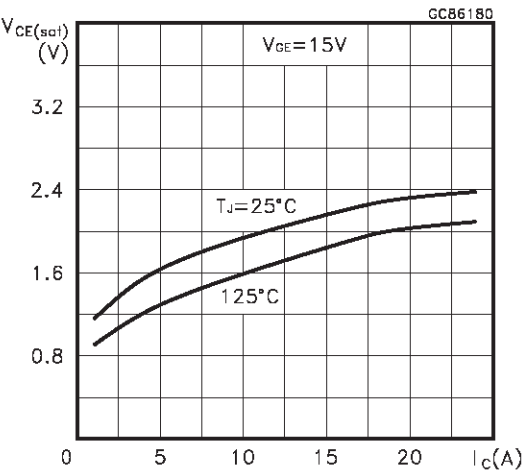
Transconductance



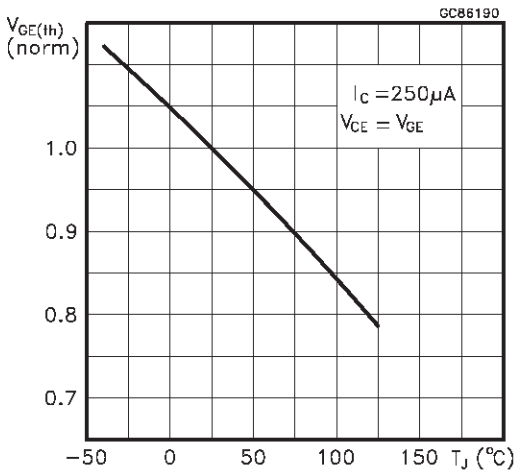
Collector-Emitter On Voltage vs Temperature



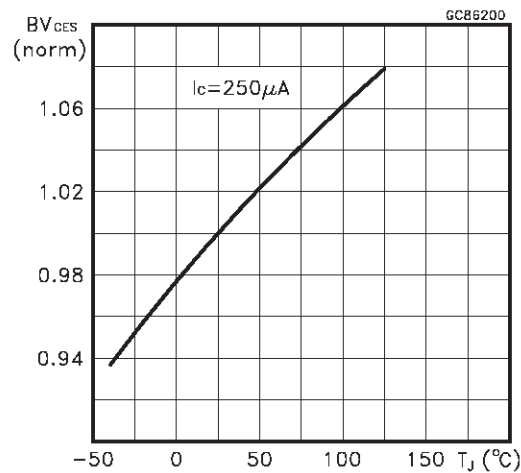
Collector-Emitter On Voltage vs Collector Current



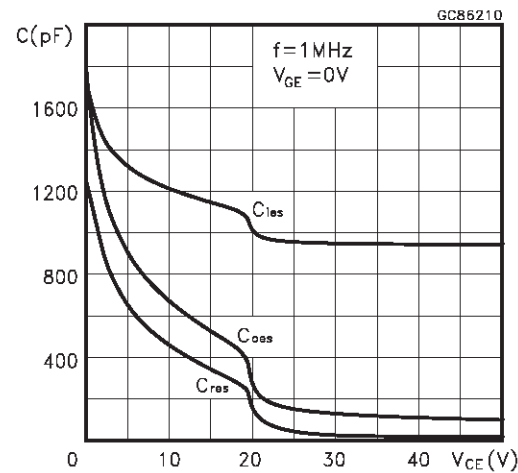
Gate Threshold vs Temperature



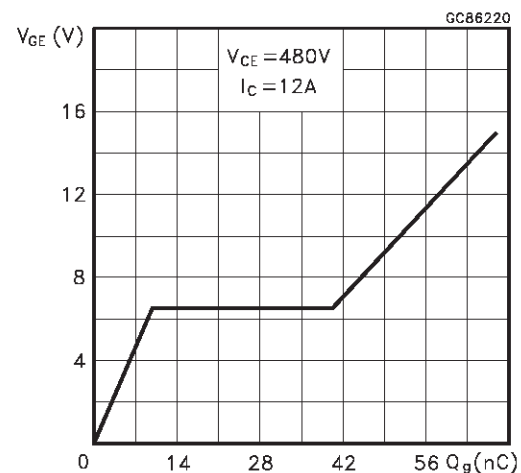
Normalized Breakdown Voltage vs Temperature



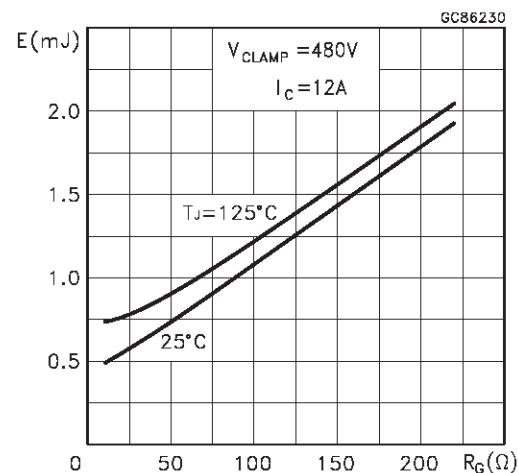
Capacitance Variations



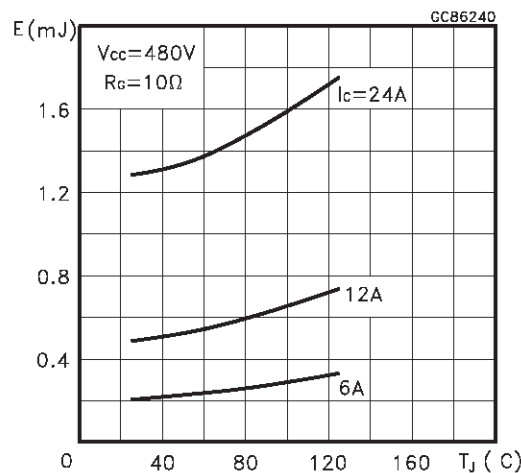
Gate Charge vs Gate-Emitter Voltage



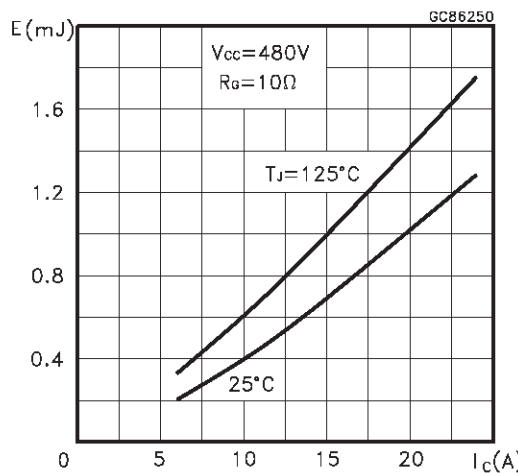
Total Switching Losses vs Gate Resistance



Total Switching Losses vs Temperature



Total Switching Losses vs Collector Current



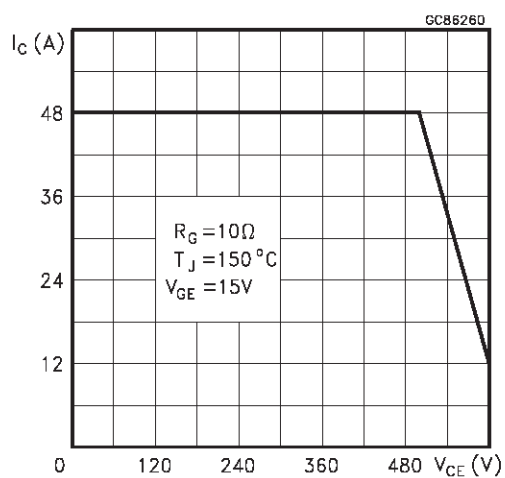


Fig. 1: Gate Charge test Circuit

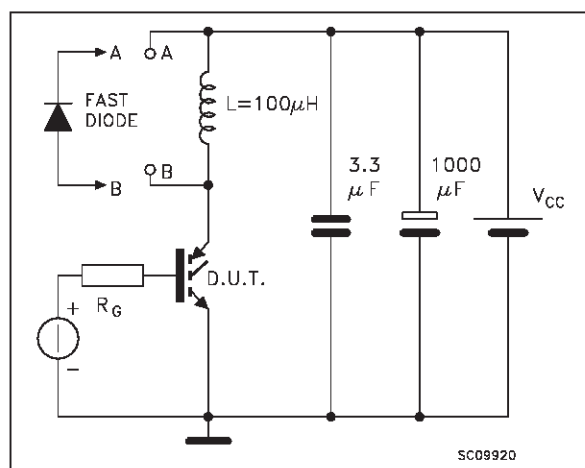
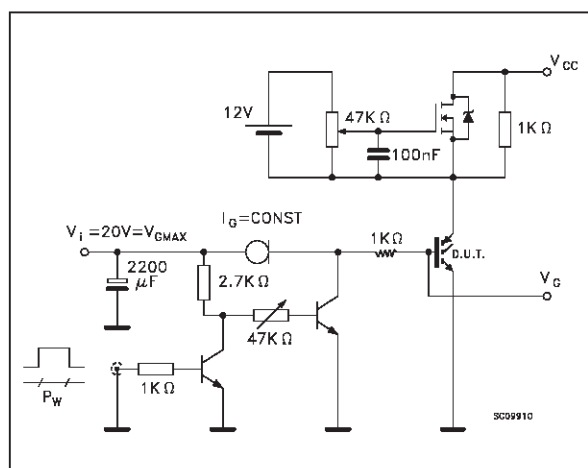
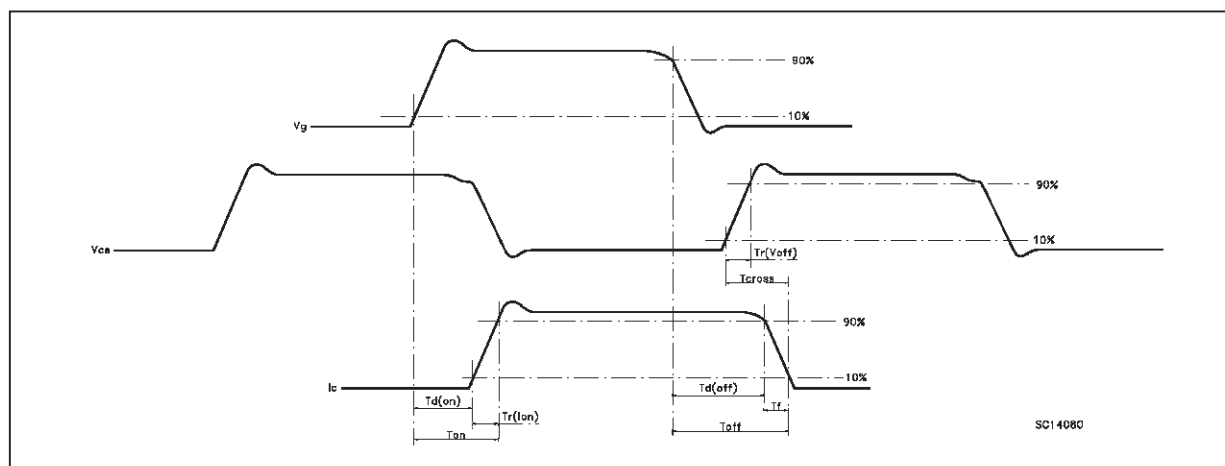
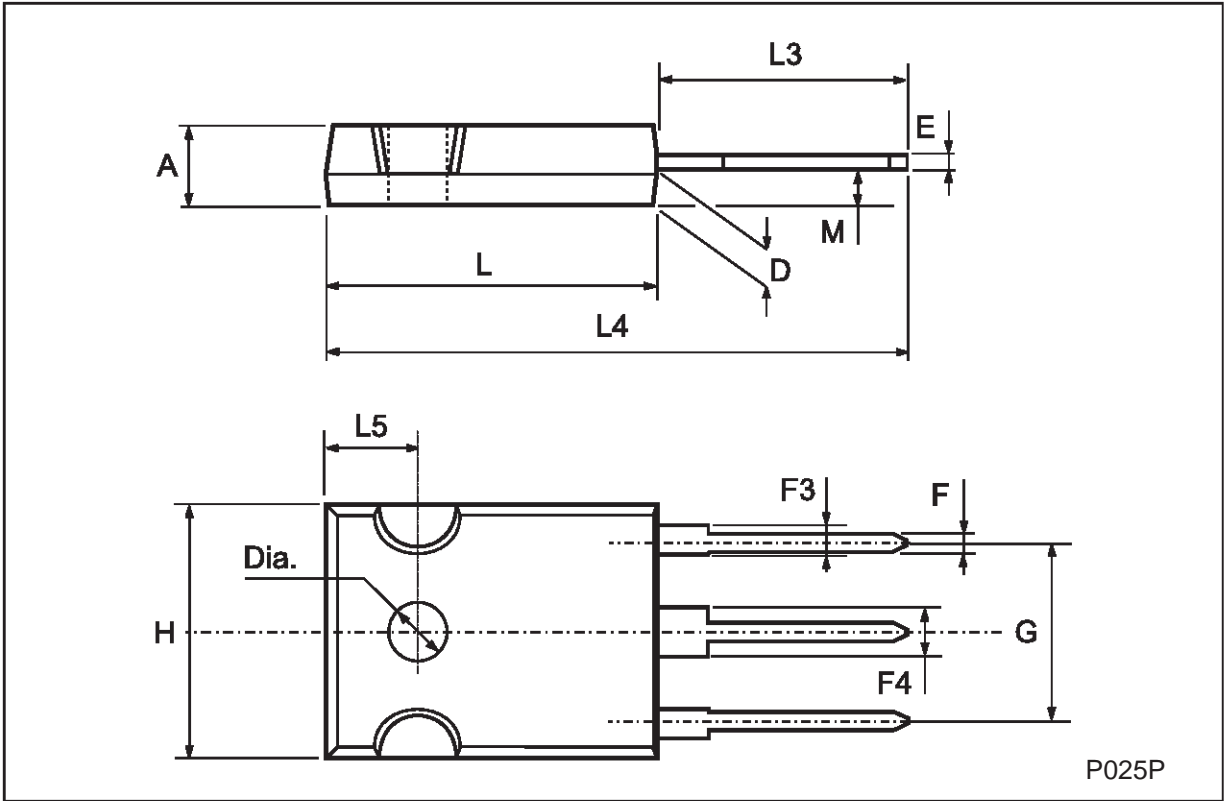


Fig. 3: Switching Waveforms



TO-247 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.7		5.3	0.185		0.209
D	2.2		2.6	0.087		0.102
E	0.4		0.8	0.016		0.031
F	1		1.4	0.039		0.055
F3	2		2.4	0.079		0.094
F4	3		3.4	0.118		0.134
G		10.9			0.429	
H	15.3		15.9	0.602		0.626
L	19.7		20.3	0.776		0.779
L3	14.2		14.8	0.559		0.582
L4		34.6			1.362	
L5		5.5			0.217	
M	2		3	0.079		0.118



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